ILNAS

Institut luxembourgeois de la normalisation
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ILNAS-EN 60749-5:2017

Semiconductor devices - Mechanical and climatic test methods - Part 5: Steady-state temperature humidity bias life test

Halbleiterbauelemente - Mechanische und klimatische Prüfverfahren - Teil 5: Lebensdauerprüfung bei konstanter Temperatur und Feuchte unter

Dispositifs à semiconducteurs - Méthodes d'essais mécaniques et climatiques - Partie 5: Essai continu de durée de vie sous température et humidité avec

07/2017

National Foreword

This European Standard EN 60749-5:2017 was adopted as Luxembourgish Standard ILNAS-EN 60749-5:2017.

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- Participate in the design of standards
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EUROPEAN STANDARD EN 60749-5

NORME EUROPÉENNE

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English Version

Semiconductor devices - Mechanical and climatic test methods - Part 5: Steady-state temperature humidity bias life test (IEC 60749-5:2017)

Dispositifs à semiconducteurs - Méthodes d'essais mécaniques et climatiques - Partie 5: Essai continu de durée de vie sous température et humidité avec polarisation (IEC 60749-5:2017)

Halbleiterbauelemente - Mechanische und klimatische Prüfverfahren - Teil 5: Lebensdauerprüfung bei konstanter Temperatur und Feuchte unter elektrischer Beanspruchung (IEC 60749-5:2017)

This European Standard was approved by CENELEC on 2017-05-15. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

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European foreword

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The following dates are fixed:

• latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement	(dop)	2018-02-15
• latest date by which the national standards conflicting with the document have to be withdrawn	(dow)	2020-05-15

This document supersedes EN 60749-5:2003.

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Endorsement notice

The text of the International Standard IEC 60749-5:2017 was approved by CENELEC as a European Standard without any modification.

Annex ZA
(normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu

Publication	Year	Title	EN/HD	Year
IEC 60749-4	-	Semiconductor devices - Mechanical and climatic test methods - Part 4: Damp heat, steady state, highly accelerated stress test (HAST)	EN 60749-4	-

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CONTENTS